datacolor

ELREPHO™

PRODUCT DATA SHEET

Feature	Datacolor ELREPHO™
Instrument Type	dual-beam spectrophotometer
Measurement Geometry	diffuse illumination and 0° viewing
Illumination Source	pulsed xenon filtered to approximate D65
Sphere Diameter	152 mm / 6.0 in
Spectral Analyzer	proprietary SP2000 analyzer with dual 256 diode array and high resolution holographic grating
Wavelength Range	360 nm to 700 nm
Reporting Interval	10 nm
Effective Bandwidth	10 nm
Wavelength Resolution	2 nm
Photometric Range:	0 to 200%
Photometric Resolution	0.003%
Black Trap	high performance
20 Read Repeatability On The White Tile Using Dual Flash (CIELAB)	0.02 (max)
Inter-instrument Agreement[1] (CIELAB)	0.4 (maximum) 0.2 (average)
Lens	3 position auto zoom
XLAV Aperture plate	34 mm illuminated and 30 mm measured
SAV Aperture plate	9 mm illuminated and 5 mm measured
USAV Aperture plate	6.5 mm illuminated and 2.5 mm measured
Automatic UV Control	automatic UV calibration for the measurement of fluorescent specimens with UV cutoff filters at 395 nm, 420 nm and 460 nm
Vertical Mount	includes peephole sample viewer and pedestal sample holder
Height	597 mm / 23.5 in
Width	312 mm / 12.3 in
Depth	381 mm / 15.0 in
Weight	17.24 kg / 38 lb
Power Requirements	85 to 264 VAC, 47 to 63 Hz, 80 VA peak, 35 VA typical
Absolute Operating Range	5° to 40° C, 5% to 85% non-condensing relative humidity
Interface	RS-232 9600/19200 baud

[1] Environmental conditions apply.